


<b>Search Notes</b>  	<b>Application/Control No.</b>  10567747	<b>Applicant(s)/Patent Under Reexamination</b>  TAKEDA ET AL.
	<b>Examiner</b>  HELEN SHIBRU	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner
386	46,124,98,95	06/2010	hs

SEARCH NOTES		
Search Notes	Date	Examiner
performed text+ searh	06/2010	hs
inventor search	06/2010	hs
consulted with Thai Tran	06/2010	hs

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	performed interference search	06/2010	hs

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